

## TC74AC138P, TC74AC138F, TC74AC138FN, TC74AC138FT

### 3-to-8 Line Decoder

The TC74AC138 is an advanced high speed CMOS 3-to-8 LINE DECODER fabricated with silicon gate and double-layer metal wiring C2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

When the device is enabled, 3 Binary Select inputs (A, B and C) determine which one of the outputs ( $\overline{Y}0 - \overline{Y}7$ ) will go low.

When enable input G1 is held low or either  $\overline{G}2A$  or  $\overline{G}2B$  is held high, decoding function is inhibited and all outputs go high.

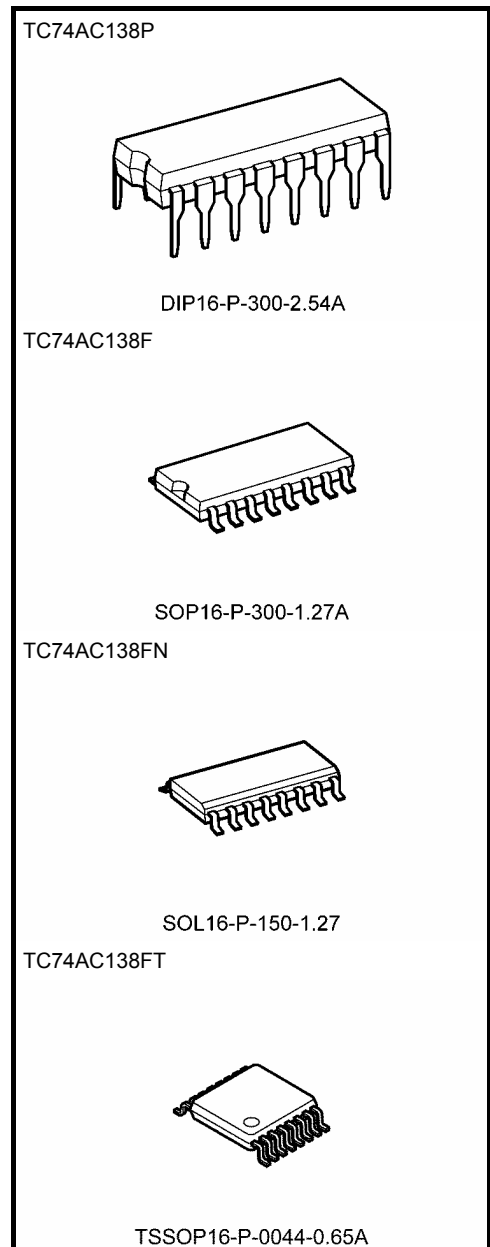
G1,  $\overline{G}2A$ , and  $\overline{G}2B$  inputs are provided to ease cascade connection and for use as an address decoder for memory systems.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

### Features

- High speed:  $t_{pd} = 5.9$  ns (typ.) at  $V_{CC} = 5$  V
- Low power dissipation:  $I_{CC} = 8$   $\mu$ A (max) at  $T_a = 25^\circ$ C
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\%$   $V_{CC}$  (min)
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 24$  mA (min)  
Capability of driving 50  $\Omega$  transmission lines.
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range:  $V_{CC} (opr) = 2$  to 5.5 V
- Pin and function compatible with 74F138

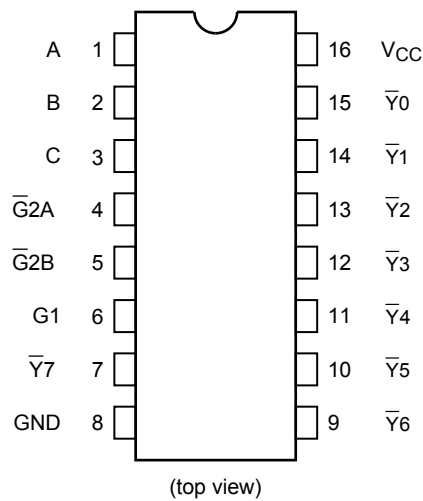
Note: xxxFN (JEDEC SOP) is not available in Japan.



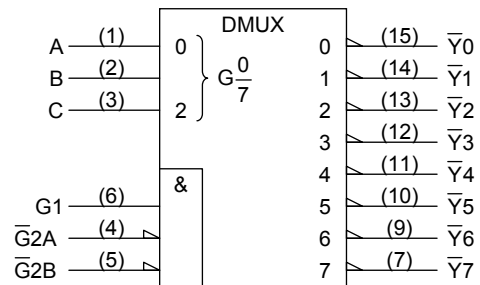
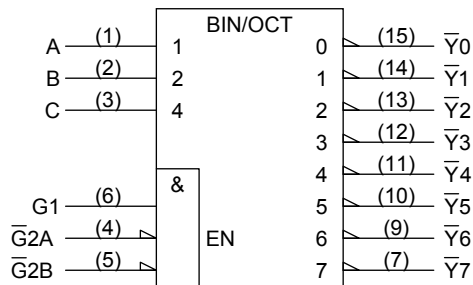
#### Weight

DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)
SOL16-P-150-1.27	: 0.13 g (typ.)
TSSOP16-P-0044-0.65A	: 0.06 g (typ.)

## Pin Assignment



## IEC Logic Symbol

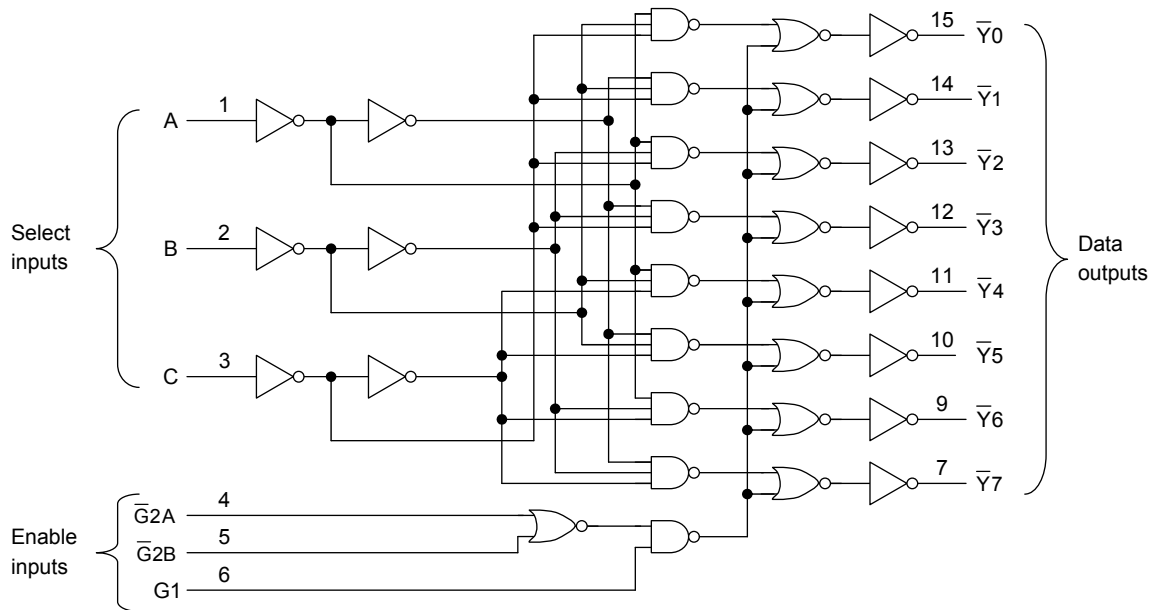


## Truth Table

Inputs						Outputs								Selected Output
Enable			Select			$\bar{Y}0$	$\bar{Y}1$	$\bar{Y}2$	$\bar{Y}3$	$\bar{Y}4$	$\bar{Y}5$	$\bar{Y}6$	$\bar{Y}7$	
G1	$\bar{G}2A$	$\bar{G}2B$	C	B	A									
L	X	X	X	X	X	H	H	H	H	H	H	H	H	None
X	H	X	X	X	X	H	H	H	H	H	H	H	H	None
X	X	H	X	X	X	H	H	H	H	H	H	H	H	None
H	L	L	L	L	L	L	H	H	H	H	H	H	H	$\bar{Y}0$
H	L	L	L	L	H	H	L	H	H	H	H	H	H	$\bar{Y}1$
H	L	L	L	H	L	H	H	L	H	H	H	H	H	$\bar{Y}2$
H	L	L	L	H	H	H	H	H	L	H	H	H	H	$\bar{Y}3$
H	L	L	H	L	L	H	H	H	H	L	H	H	H	$\bar{Y}4$
H	L	L	H	L	H	H	H	H	H	H	L	H	H	$\bar{Y}5$
H	L	L	H	H	L	H	H	H	H	H	H	L	H	$\bar{Y}6$
H	L	L	H	H	H	H	H	H	H	H	H	H	L	$\bar{Y}7$

X: Don't care

**Logic Diagram**



**Absolute Maximum Ratings (Note 1)**

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	-0.5 to 7.0	V
DC input voltage	$V_{IN}$	-0.5 to $V_{CC} + 0.5$	V
DC output voltage	$V_{OUT}$	-0.5 to $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$	$\pm 20$	mA
Output diode current	$I_{OK}$	$\pm 50$	mA
DC output current	$I_{OUT}$	$\pm 50$	mA
DC $V_{CC}$ /ground current	$I_{CC}$	$\pm 200$	mA
Power dissipation	$P_D$	500 (DIP) (Note 2)/180 (SOP/TSSOP)	mW
Storage temperature	$T_{stg}$	-65 to 150	$^{\circ}C$

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of  $T_a = -40$  to  $65^{\circ}C$ . From  $T_a = 65$  to  $85^{\circ}C$  a derating factor of  $-10$  mW/ $^{\circ}C$  should be applied up to 300 mW.

**Operating Ranges (Note)**

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	2.0 to 5.5	V
Input voltage	$V_{IN}$	0 to $V_{CC}$	V
Output voltage	$V_{OUT}$	0 to $V_{CC}$	V
Operating temperature	$T_{opr}$	-40 to 85	$^{\circ}C$
Input rise and fall time	dt/dV	0 to 100 ( $V_{CC} = 3.3 \pm 0.3$ V) 0 to 20 ( $V_{CC} = 5 \pm 0.5$ V)	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{CC}$  or GND.

## Electrical Characteristics

### DC Characteristics

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Ta = 25°C			Ta = -40 to 85°C		Unit	
				Min	Typ.	Max	Min	Max		
High-level input voltage	V <sub>IH</sub>	—	2.0	1.5	—	—	1.5	—	V	
			3.0	2.10	—	—	2.10	—		
			5.5	3.85	—	—	3.85	—		
Low-level input voltage	V <sub>IL</sub>	—	2.0	—	—	0.50	—	0.50	V	
			3.0	—	—	0.90	—	0.90		
			5.5	—	—	1.65	—	1.65		
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	2.0	—	1.9	—	V
				3.0	2.9	3.0	—	2.9	—	
			I <sub>OH</sub> = -4 mA	3.0	2.58	—	—	2.48	—	
			I <sub>OH</sub> = -24 mA	4.5	3.94	—	—	3.80	—	
		I <sub>OH</sub> = -75 mA (Note)	5.5	—	—	—	3.85	—		
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 50 μA	2.0	—	0.0	0.1	—	0.1	V
				3.0	—	0.0	0.1	—	0.1	
				4.5	—	0.0	0.1	—	0.1	
			I <sub>OL</sub> = 12 mA	3.0	—	—	0.36	—	0.44	
			I <sub>OL</sub> = 24 mA	4.5	—	—	0.36	—	0.44	
		I <sub>OL</sub> = 75 mA (Note)	5.5	—	—	—	—	1.65		
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	5.5	—	—	±0.1	—	±1.0	μA	
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND	5.5	—	—	8.0	—	80.0	μA	

Note: This spec indicates the capability of driving 50 Ω transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

## AC Characteristics ( $C_L = 50 \text{ pF}$ , $R_L = 500 \text{ } \Omega$ , input: $t_r = t_f = 3 \text{ ns}$ )

Characteristics	Symbol	Test Condition	$V_{CC}$ (V)	$T_a = 25^\circ\text{C}$			$T_a = -40 \text{ to } 85^\circ\text{C}$		Unit
				Min	Typ.	Max	Min	Max	
Propagation delay time (A, B, C- $\bar{Y}$ )	$t_{pLH}$	—	$3.3 \pm 0.3$	—	8.5	14.2	1.0	16.3	ns
	$t_{pHL}$		$5.0 \pm 0.5$	—	6.4	9.2	1.0	10.5	
Propagation delay time (G1- $\bar{Y}$ )	$t_{pLH}$	—	$3.3 \pm 0.3$	—	7.5	12.8	1.0	14.7	ns
	$t_{pHL}$		$5.0 \pm 0.5$	—	6.1	8.9	1.0	10.2	
Propagation delay time ( $\bar{G}2$ - $\bar{Y}$ )	$t_{pLH}$	—	$3.3 \pm 0.3$	—	8.8	15.0	1.0	17.3	ns
	$t_{pHL}$		$5.0 \pm 0.5$	—	7.2	10.5	1.0	12.0	
Input capacitance	$C_{IN}$	—	—	5	10	—	10	pF	
Power dissipation capacitance	$C_{PD}$	(Note)	—	143	—	—	—	pF	

Note:  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

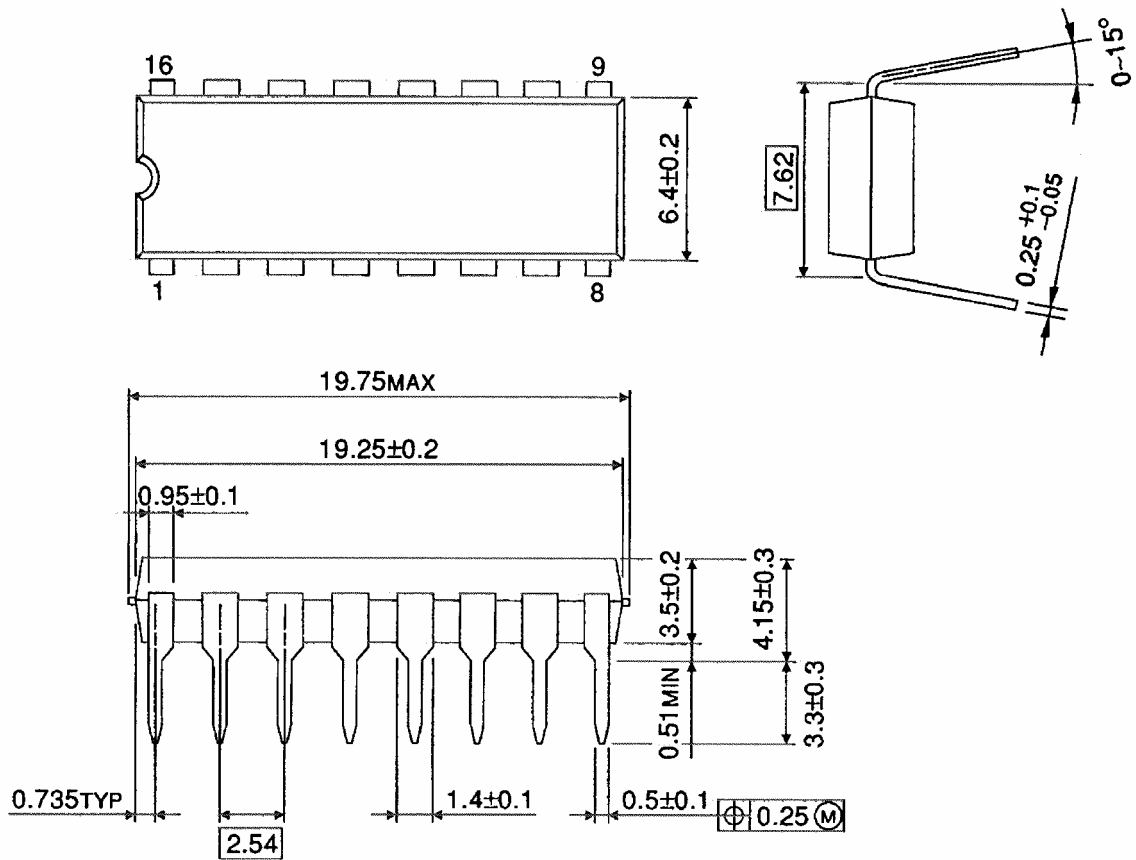
Average operating current can be obtained by the equation:

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

## Package Dimensions

DIP16-P-300-2.54A

Unit : mm

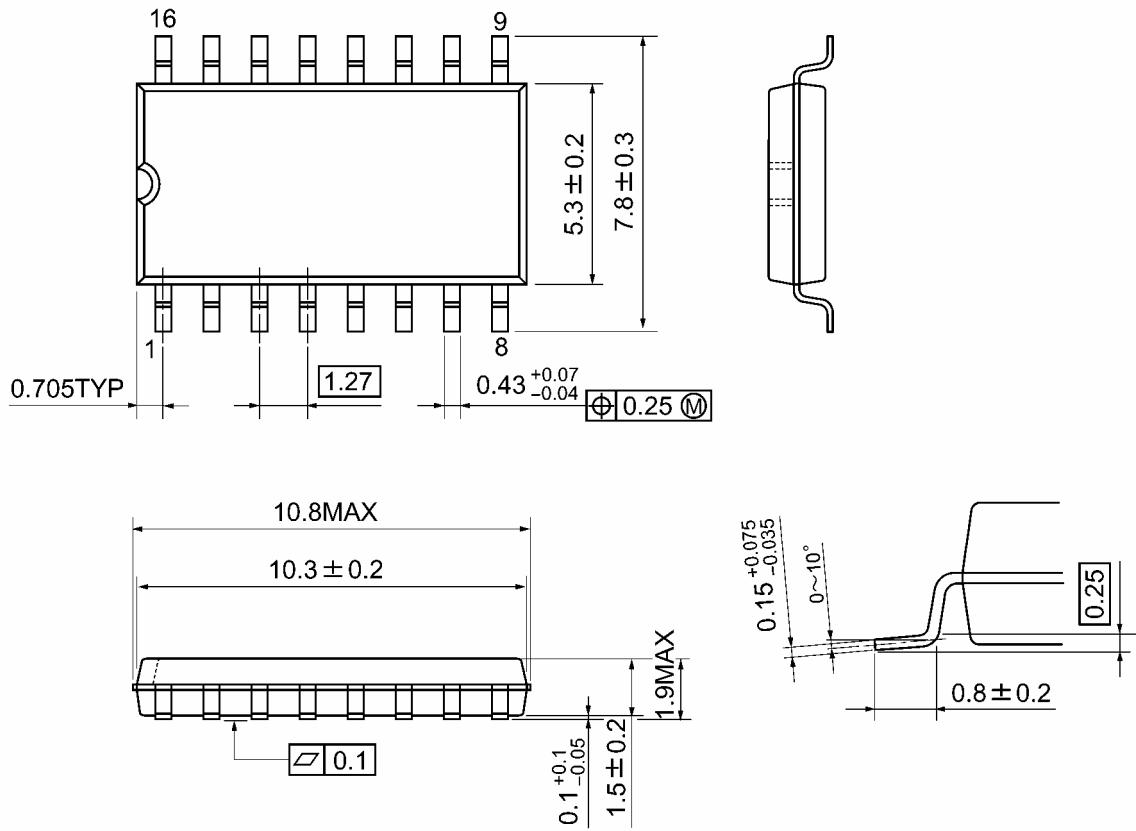


Weight: 1.00 g (typ.)

**Package Dimensions**

SOP16-P-300-1.27A

Unit: mm

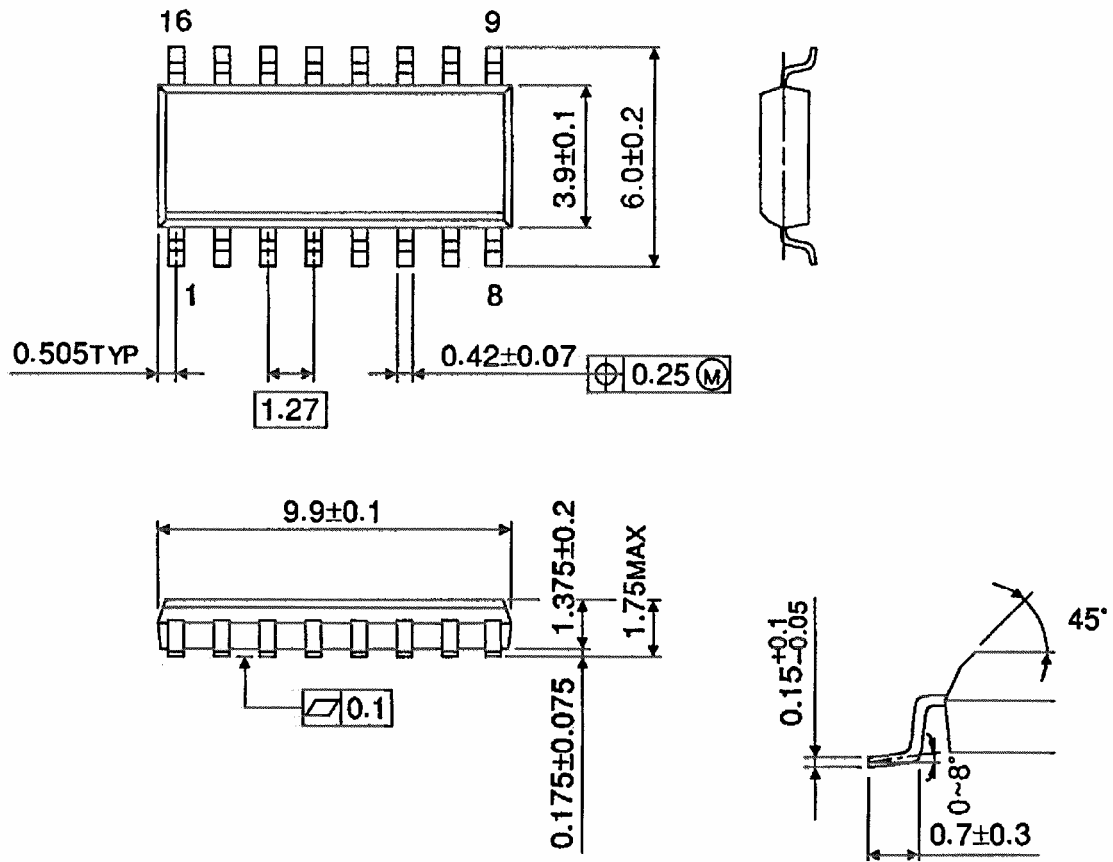


Weight: 0.18 g (typ.)

## Package Dimensions (Note)

SOL16-P-150-1.27

Unit : mm



Note: This package is not available in Japan.

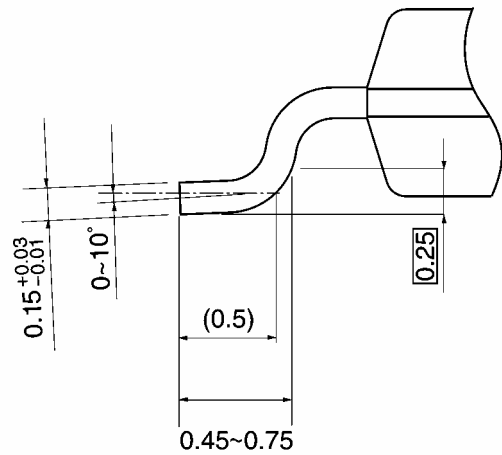
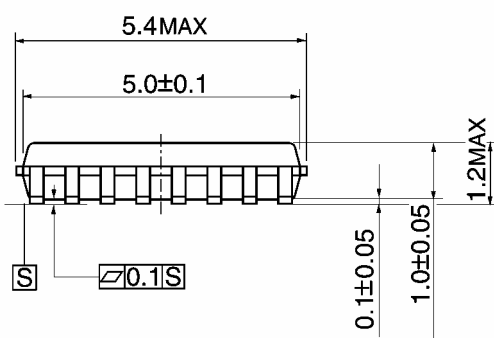
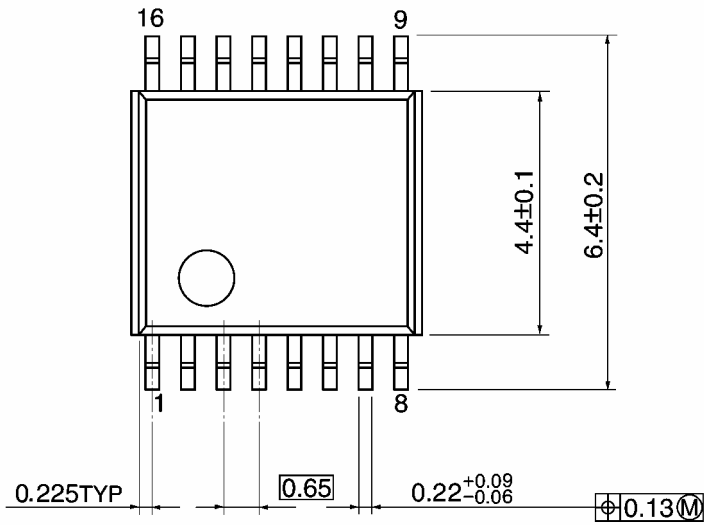
Weight: 0.13 g (typ.)



**Package Dimensions**

TSSOP16-P-0044-0.65A

Unit: mm



Weight: 0.06 g (typ.)

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20070701-EN GENERAL

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